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LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)

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M	AV	6	1	3	6	6	6	8	10/00	Tamaki et al.	438	462		-
M	AW	6	4	4	1	3	0	0	08/27/02	Sannomiya et al.	136	251		
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LIST OF DOCUMENTS CITED BY APPLICANT

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FILING DATE GROUP

December 2, 2003 Unknown

U.S. PATENT DOCUMENTS

EXAMINER			DO	CUM	ENT	NUM	BER		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF
M	AA	4	8	9	2	5	9	2	01/09/90	Dickson et al.	136	244	
1	AB	4	7	2	4	0	1	1	02/09/88	Turner et al.	136	249	
	AC	4	7	2	1	6	2	9	01/26/88	Sakai et al.	427	35	
	AD	5	1	7	6	7	5	8	01/05/93	Nath et al.	136	251	
	AE	4	2	9	2	0	9	2	09/29/81	Joseph J. Hanak	148	1.5	
	AF	5	2	5	4	1	7	9	10/19/93	Ricaud et al.	136	244	
_	AG	4	7	9	5	5	0	0	01/03/89	Kishi et al.	136	244	
	AH	6	2	6	5	6	5	2	07/01	Kurata et al.	136	244	
	Al	6	4	5	5	3	4	7	09/02	Hiraishi et al.	438	80	
V	AJ	5	4	6	8	6	5	2	11/95	Gee	437	2	
MI	AK	5	6	9	3	1	8	1	12/97	Bernstein	156	644.1	

FOREIGN PATENT DOCUMENTS

			DOCUMENT NUMBER						DATE	COUNTRY	CLASS	SUBCLASS	TRANSL YES	ATION NO
M	AL	JP	63	28	9	9	6	9	11/28/88	Japan (Patent Abstract)			_	
	AM				<u> </u>									
	AN													
	AO													
	AP													

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

M	AR	Article, Ronald D. Schaeffer and Ilias Syrgabaev, Solar Electricity Shines, January 2001 Issue of Industrial Laser Solutions, pp. 33-34
My	AS	Leppanen, et al., "Manufacturing Options for Large a-Si PV Façade Elements," Engineering Conference, Vienna, Austria, July 6-10, 1998, Vol. 3, July 6, 1998, pp. 2575-2578
M	AT	Stark et al., "Konstruktive Varianten Beim Modulaufbau, "Photovoltaik Archiektonische Gebaeudeintegration, XX, XX, July 2000, pp. 10-15; 18-19; 25-26 and 32-37.

EXAMINER DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.